

## Notic of References Cited

Application/Control No. 09/466,895

Applicant(s)/Patent Under Reexamination IIJIMA ET AL.

Examiner

Sean P Smith

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Art Unit

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## U.S. PATENT DOCUMENTS

			Date	U.S. PATERT DOCUMENTS	Oleanif	
*		Document Number Country Code-Number-Kind Code	MM-YYYY	Name	Classif	
	Α	US-US006280858B	08-2001	Teshima	428	639
	В	US-US006258631B	07-2001	Ito et al.	438	123
	С	US-US006020626A	02-2000	Ohsawa et al.	257	668
	D	US-5728599	03-1998	Rostoker et al.	437	182
	E	US-5756377	05-1998	Ohsawa	438	111
	F	US-5602059	02-1997	Horiuchi et al.	437	209
	G	US-5662755	09-1997	Miura et al.	156	89
	Н	US-US005663106A	09-1997	Karavakis et al.	29	841
	''	US-5686702	11-1997	Ishida	174	250
	<del>                                     </del>	US-US005481798A	01-1996	Ohsawa	29	827
	] ]	US-5027188	06-1997	Owada et al.	357	68
	K		06-1980	Burns	156	630
	<u> </u>	US-4209355	01-1979	Price	29	623
	М	US-4135295	01-1979	TODESON PATENT DOCUMENTS		<u> </u>

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date Country	Name	Classification		
	N	2215144	02-1990	Japan			
	0	11204680	11-1999	Japan			
	Р	637151	06-1994	Japan			
-	Q	5563857	05-1980	Japan			
	R	1154668	02-1999	Japan			
	s	57188859	11-1982	Japan			
	Т	·				<u> </u>	<u></u>

## NON-PATENT DOCUMENTS

NON-PATENT DOCUMENTS				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U			
	v			
	w			
	x	(See MPEP § 707.05(a).)		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

